# IGBT with Monolithic Free Wheeling Diode

This Insulated Gate Bipolar Transistor (IGBT) features a robust and cost effective Field Stop (FS) Trench construction, provides superior performance in demanding switching applications, and offers low on–state voltage with minimal switching losses. The IGBT is well suited for resonant or soft switching applications.

#### **Features**

- Extremely Efficient Trench with Fieldstop Technology
- 1350 V Breakdown Voltage
- Optimized for Low Losses in IH Cooker Application
- Reliable and Cost Effective Single Die Solution
- These are Pb-Free Devices

## **Typical Applications**

- Inductive Heating
- Consumer Appliances
- Soft Switching

## **ABSOLUTE MAXIMUM RATINGS**

Rating	Symbol	Value	Unit
Collector-emitter voltage @ T <sub>J</sub> = 25°C	V <sub>CES</sub>	1350	V
Collector current @ Tc = 25°C @ Tc = 100°C	Ι <sub>C</sub>	60 30	А
Pulsed collector current, $T_{pulse}$ limited by $T_{Jmax}$ 10 $\mu s$ pulse, $V_{GE}$ = 15 $V$	I <sub>CM</sub>	120	Α
Diode forward current @ Tc = 25°C @ Tc = 100°C	I <sub>F</sub>	60 30	A
Diode pulsed current, $T_{pulse}$ limited by $T_{Jmax}$ 10 $\mu s$ pulse, $V_{GE}$ = 0 $V$	I <sub>FM</sub>	120	Α
Gate-emitter voltage Transient Gate-emitter Voltage ( $T_{pulse} = 5 \mu s$ , D < 0.10)	$V_{GE}$	±20 ±25	V
Power Dissipation @ Tc = 25°C @ Tc = 100°C	P <sub>D</sub>	394 197	W
Operating junction temperature range	TJ	-40 to +175	°C
Storage temperature range	T <sub>stg</sub>	-55 to +175	°C
Lead temperature for soldering, 1/8" from case for 5 seconds	T <sub>SLD</sub>	260	°C

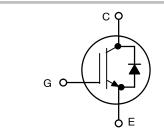
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

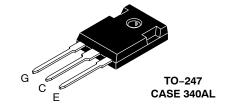


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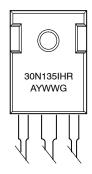
http://onsemi.com

30 A, 1350 V V<sub>CEsat</sub> = 2.30 V E<sub>off</sub> = 0.85 mJ





## **MARKING DIAGRAM**



A = Assembly Location

Y = Year WW = Work Week G = Pb-Free Package

#### **ORDERING INFORMATION**

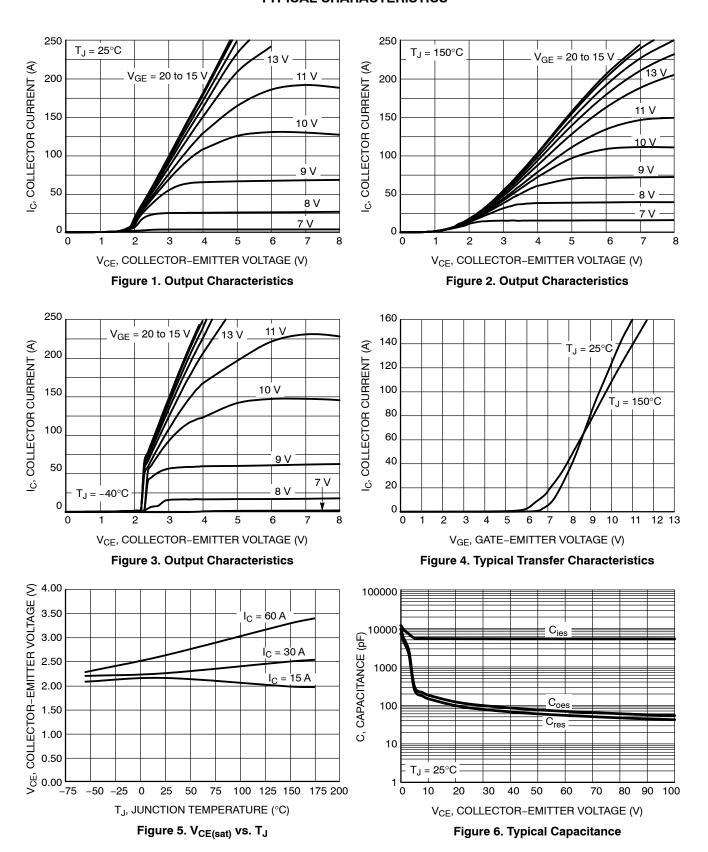
Device	Package	Shipping
NGTB30N135IHRWG	TO-247 (Pb-Free)	30 Units / Rail

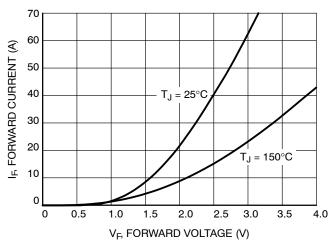
## THERMAL CHARACTERISTICS

Rating	Symbol	Value	Unit
Thermal resistance junction-to-case	$R_{ heta JC}$	0.38	°C/W
Thermal resistance junction-to-ambient	$R_{ heta JA}$	40	°C/W

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
STATIC CHARACTERISTIC		•				
Collector-emitter breakdown voltage, gate-emitter short-circuited	$V_{GE} = 0 \text{ V, I}_{C} = 5 \text{ mA}$	V <sub>(BR)CES</sub>	1350	_	-	V
Collector-emitter saturation voltage	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 30 A V <sub>GE</sub> = 15 V, I <sub>C</sub> = 30 A, T <sub>J</sub> = 175°C	V <sub>CEsat</sub>	- -	2.30 2.50	2.65 -	V
Gate-emitter threshold voltage	$V_{GE} = V_{CE}, I_{C} = 250 \mu A$	V <sub>GE(th)</sub>	4.5	5.5	6.5	V
Collector-emitter cut-off current, gate- emitter short-circuited	$V_{GE} = 0 \text{ V}, V_{CE} = 1350 \text{ V}$ $V_{GE} = 0 \text{ V}, V_{CE} = 1350 \text{ V}, T_{J=} 175^{\circ}\text{C}$	I <sub>CES</sub>	- -	- -	0.5 2.0	mA
Gate leakage current, collector-emitter short-circuited	V <sub>GE</sub> = 20 V, V <sub>CE</sub> = 0 V	I <sub>GES</sub>	-	_	100	nA
DYNAMIC CHARACTERISTIC					-	
Input capacitance		C <sub>ies</sub>	-	5290	_	pF
Output capacitance	V <sub>CE</sub> = 20 V, V <sub>GE</sub> = 0 V, f = 1 MHz	C <sub>oes</sub>	-	124	-	
Reverse transfer capacitance		C <sub>res</sub>	-	100	-	
Gate charge total		$Q_g$	-	234	_	nC
Gate to emitter charge	$V_{CE}$ = 600 V, $I_{C}$ = 30 A, $V_{GE}$ = 15 V	$Q_{ge}$	-	39	_	
Gate to collector charge		Q <sub>gc</sub>	-	105	_	]
SWITCHING CHARACTERISTIC, INDUCT	TIVE LOAD					
Turn-off delay time	T <sub>J</sub> = 25°C	t <sub>d(off)</sub>	-	250	_	ns
Fall time	$V_{CC} = 600 \text{ V}, I_{C} = 30 \text{ A}$ $R_{\alpha} = 10 \Omega$	t <sub>f</sub>	-	150	_	
Turn-off switching loss	V <sub>GE</sub> = 0 V/ 15V	E <sub>off</sub>	-	0.85	_	mJ
Turn-off delay time	T <sub>J</sub> = 150°C	t <sub>d(off)</sub>	-	265	_	ns
Fall time	$V_{CC} = 600 \text{ V}, I_{C} = 30 \text{ A}$ $R_{\alpha} = 10 \Omega$	t <sub>f</sub>	-	225	-	
Turn-off switching loss	$V_{GE} = 0 \text{ V} / 15 \text{V}$	E <sub>off</sub>	-	1.90	_	mJ
DIODE CHARACTERISTIC			_		_	
Forward voltage	$V_{GE} = 0 \text{ V, I}_F = 30 \text{ A}$ $V_{GE} = 0 \text{ V, I}_F = 30 \text{ A, T}_J = 175^{\circ}\text{C}$	V <sub>F</sub>	_ _	2.10 3.20	2.40 -	V

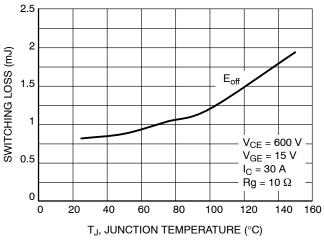




16 V<sub>GE</sub>, GATE-EMITTER VOLTAGE (V) 14 12 10 6 V<sub>CE</sub> = 600 V 2 V<sub>GE</sub> = 15 V I<sub>C</sub> = 30 A 0 0 50 100 150 200 250 Q<sub>G</sub>, GATE CHARGE (nC)

Figure 7. Diode Forward Characteristics

Figure 8. Typical Gate Charge



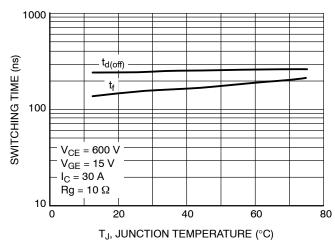
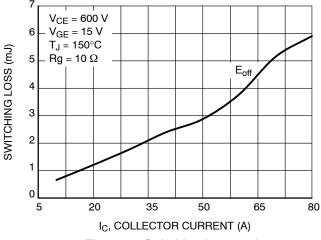


Figure 9. Switching Loss vs. Temperature

Figure 10. Switching Time vs. Temperature



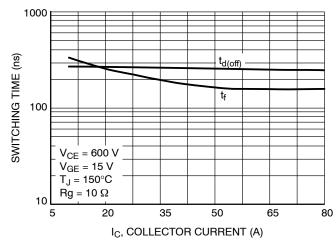
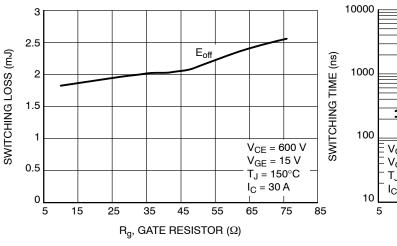


Figure 11. Switching Loss vs. I<sub>C</sub>

Figure 12. Switching Time vs. I<sub>C</sub>



10000

1000

V<sub>CE</sub> = 600 V

V<sub>GE</sub> = 15 V

T<sub>J</sub> = 150°C

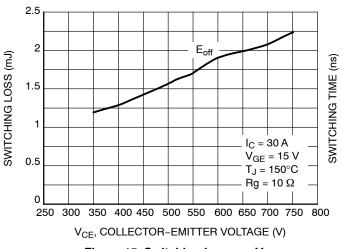
I<sub>C</sub> = 30 A

5 15 25 35 45 55 65 75 85

R<sub>g</sub>, GATE RESISTOR (Ω)

Figure 13. Switching Loss vs. Ra

Figure 14. Switching Time vs.  $R_g$ 



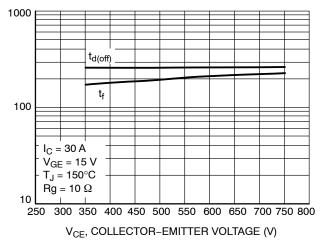
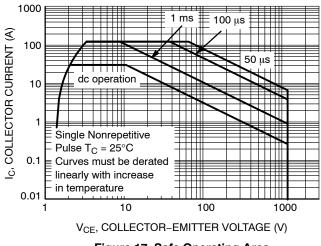


Figure 15. Switching Loss vs. V<sub>CE</sub>

Figure 16. Switching Time vs. V<sub>CE</sub>



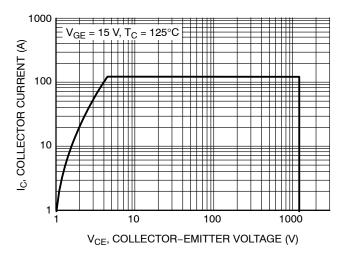


Figure 17. Safe Operating Area

Figure 18. Reverse Bias Safe Operating Area

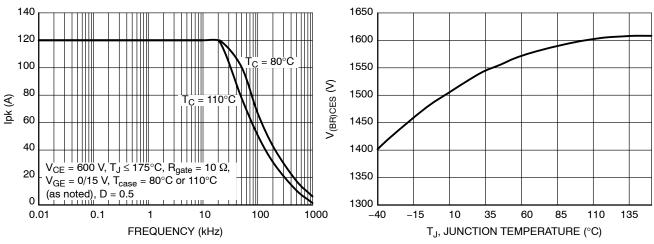


Figure 19. Collector Current vs. Switching Frequency

Figure 20. Typical  $V_{(BR)CES}$  vs. Temperature

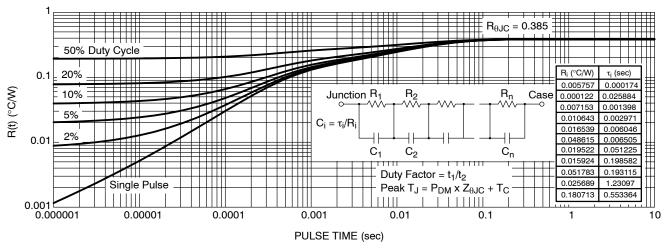


Figure 21. IGBT Transient Thermal Impedance

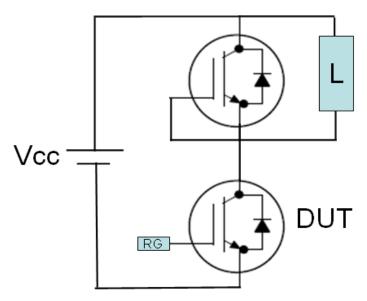


Figure 22. Test Circuit for Switching Characteristics

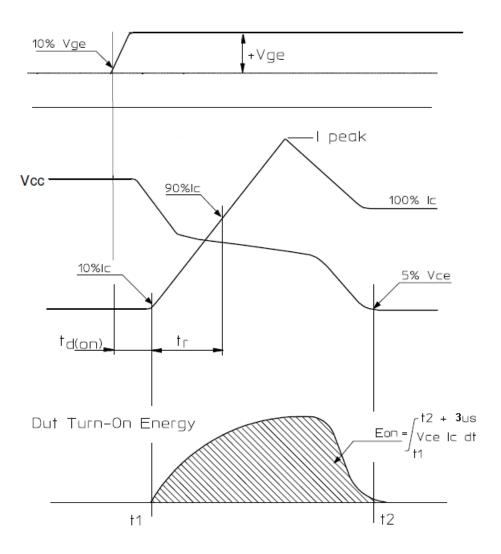


Figure 23. Definition of Turn On Waveform

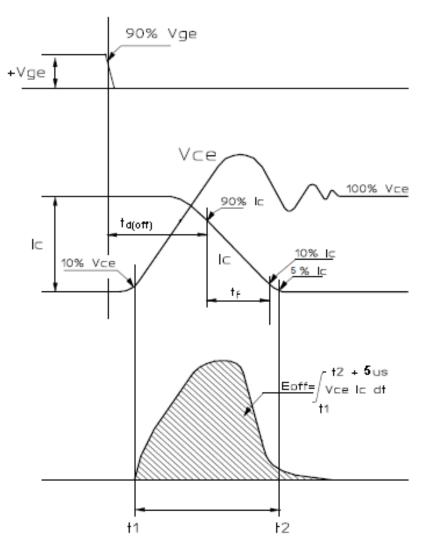
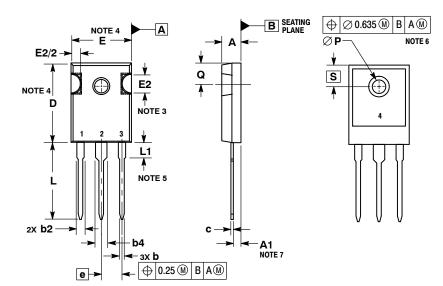


Figure 24. Definition of Turn Off Waveform

#### PACKAGE DIMENSIONS

#### TO-247 CASE 340AL **ISSUE A**



#### NOTES:

- 1 DIMENSIONING AND TOLERANCING PER ASME Y14 5M 1994
- CONTROLLING DIMENSION: MILLIMETERS.
- SLOT REQUIRED, NOTCH MAY BE ROUNDED.
  DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.13 PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST
- EXTREME OF THE PLASTIC BODY.
  LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY
- ØP SHALL HAVE A MAXIMUM DRAFT ANGLE OF 1.5° TO THE
- TOP OF THE PART WITH A MAXIMUM DIAMETER OF 3.91.
  DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED

	MILLIMETERS		
DIM	MIN	MAX	
Α	4.70	5.30	
A1	2.20	2.60	
b	1.00	1.40	
b2	1.65	2.35	
b4	2.60	3.40	
C	0.40	0.80	
n	20.30	21 40	

15.50 16.25 E2 5.49 4.32 5.45 BSC 19.80 20.80 L1 3.50 4.50 5.40 6.20 6.15 BSC

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